

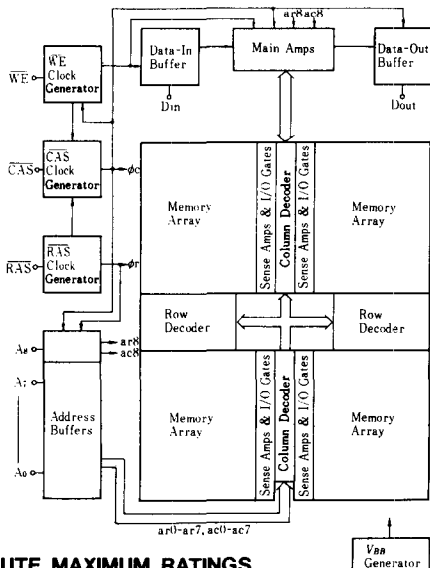
HM50256-12, HM50256-15, HM50256-20, HM50256P-12, HM50256P-15, HM50256P-20

262144-word × 1-bit Dynamic Random Access Memory

■ FEATURES

- Industry Standard 16-Pin DIP
- Single 5V (±10%)
- On chip substrate bias generator
- Low Power: 350mW active, 20mW standby
- High speed: Access Time 120ns/150ns/200ns(max.)
- Common I/O capability using early write operation
- Page mode capability
- TTL compatible
- 256 refresh cycles . . . (4ms)
- 3 variations of refresh . . . $\overline{\text{RAS}}$ only refresh, $\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ refresh, Hidden refresh

■ BLOCK DIAGRAM



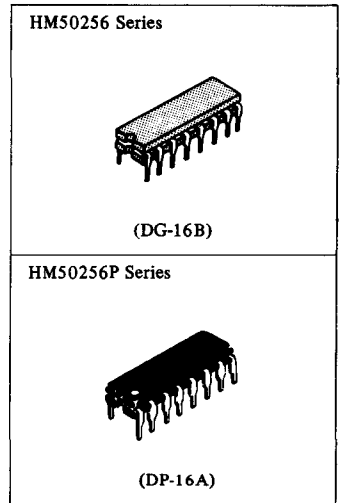
■ ABSOLUTE MAXIMUM RATINGS

- Voltage on any pin relative to V_{SS} -1V to +7V
 Operating temperature, T_a (Ambient) 0°C to +70°C
 Storage temperature (Cerdip) -65°C to +150°C
 (Plastic DIP) -55°C to +125°C
 Power dissipation 1W
 Short circuit output current 50mA

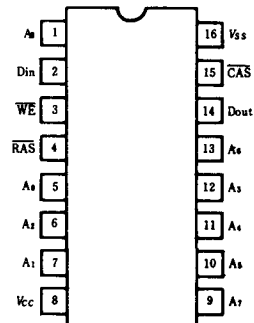
■ RECOMMENDED DC OPERATING CONDITIONS ($T_a=0$ to +70°C)

Parameter	Symbol	min	typ	max	Unit	Note
Supply Voltage	V_{CC}	4.5	5.0	5.5	V	1
Input High Voltage	V_{IH}	2.4	—	6.5	V	1
Input Low Voltage	V_{IL}	-1.0	—	0.8	V	1

Note) 1. All voltages referenced to V_{SS}



■ PIN ARRANGEMENT



(Top View)

$A_0 \sim A_8$	Address Inputs
CAS	Column Address Strobe
Din	Data In
Dout	Data Out
$\overline{\text{RAS}}$	Row Address Strobe
$\overline{\text{WE}}$	Read/Write Input
V_{CC}	Power (+5V)
V_{SS}	Ground
$A_0 \sim A_7$	Refresh Address Inputs

■ DC ELECTRICAL CHARACTERISTICS ($T_a=0$ to $+70^\circ\text{C}$, $V_{CC}=5\text{V}\pm 10\%$, $V_{SS}=0\text{V}$)

Parameter	Symbol	HM50256/P-12		HM50256/P-15		HM50256/P-20		Unit	Notes
		min	max	min	max	min	max		
Operating Current($\overline{\text{RAS}}$, $\overline{\text{CAS}}$ Cycling : $t_{AC}=\text{min}$)	I_{CC1}	—	83	—	70	—	55	mA	1
Standby Current($\overline{\text{RAS}}=V_{IH}$, $\text{Dout}=\text{High Impedance}$)	I_{CC2}	—	4.5	—	4.5	—	4.5	mA	
Refresh Current($\overline{\text{RAS}}$ only Refresh, $t_{AC}=\text{min}$)	I_{CC3}	—	62	—	53	—	42	mA	
Standby Current($\overline{\text{RAS}}=V_{IH}$, Dout Enable)	I_{CC5}	—	10	—	10	—	10	mA	1
Refresh Current($\overline{\text{CAS}}$ before $\overline{\text{RAS}}$ Refresh, $t_{AC}=\text{min}$)	I_{CC4}	—	69	—	58	—	45	mA	
Input leakage($0 < V_{in} < 7\text{V}$)	I_{LI}	-10	10	-10	10	-10	10	μA	
Output leakage($0 < V_{out} < 7\text{V}$)	I_{LO}	-10	10	-10	10	-10	10	μA	
Output levels High($I_{out} = -5\text{mA}$)	V_{OH}	2.4	V_{CC}	2.4	V_{CC}	2.4	V_{CC}	V	
Output levels Low($I_{out} = 4.2\text{mA}$)	V_{OL}	0	0.4	0	0.4	0	0.4	V	

Notes) 1. I_{CC} depends on output loading condition when the device is selected. I_{CC} max is specified at the output open condition.

■ CAPACITANCE ($V_{CC}=5\text{V}\pm 10\%$, $T_a=25^\circ\text{C}$)

Parameter	Symbol	typ	max	Unit	Notes
	Clocks, Data-out	C_{O2}	—	7	1, 2

Notes) 1. Capacitance measured with Bonton Meter or effective capacitance measuring method.
 2. $\text{CAS} = V_{IH}$ to disable Dout.

■ ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

($T_a=0$ to $+70^\circ\text{C}$, $V_{CC}=5\text{V}\pm 10\%$, $V_{SS}=0\text{V}$)^{1), 10), 11)}

Parameter	Symbol	HM50256/P-12		HM50256/P-15		HM50256/P-20		Unit	Notes
		min	max	min	max	min	max		
Access Time from $\overline{\text{RAS}}$	t_{RAC}	—	120	—	150	—	200	ns	2, 3
Access Time from $\overline{\text{CAS}}$	t_{CAC}	—	60	—	75	—	100	ns	3, 4
Output Buffer Turn-off Delay	t_{OFF}	—	30	—	40	—	50	ns	5
Transition Time(Rise and Fall)	t_T	3	50	3	50	3	50	ns	6
Random Read or Write Cycle Time	t_{RC}	220	—	260	—	330	—	ns	
$\overline{\text{RAS}}$ Precharge Time	t_{RP}	90	—	100	—	120	—	ns	
$\overline{\text{RAS}}$ Pulse Width	t_{RAS}	120	10000	150	10000	200	10000	ns	
$\overline{\text{CAS}}$ Pulse Width	t_{CAS}	60	10000	75	10000	100	10000	ns	
$\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Delay Time	t_{RCD}	25	60	25	75	30	100	ns	7
$\overline{\text{RAS}}$ Hold Time	t_{RSH}	60	—	75	—	100	—	ns	
$\overline{\text{CAS}}$ Hold Time	t_{CSH}	120	—	150	—	200	—	ns	
$\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ Precharge Time	t_{CRP}	10	—	10	—	10	—	ns	
Row Address Set-up Time	t_{ASR}	0	—	0	—	0	—	ns	
Row Address Hold Time	t_{RAH}	15	—	15	—	20	—	ns	
Column Address Set-up Time	t_{ASC}	0	—	0	—	0	—	ns	
Column Address Hold Time	t_{CAH}	20	—	25	—	30	—	ns	
Column Address Hold Time referenced to $\overline{\text{RAS}}$	t_{AR}	80	—	100	—	130	—	ns	
$\overline{\text{WE}}$ Command Set-up Time	t_{WCS}	0	—	0	—	0	—	ns	8
Write Command Hold Time	t_{WCH}	40	—	45	—	55	—	ns	
Write Command Hold Time referenced to $\overline{\text{RAS}}$	t_{WCR}	100	—	120	—	155	—	ns	
Write Command Pulse Width	t_{WP}	40	—	45	—	55	—	ns	
Write Command to $\overline{\text{RAS}}$ Lead Time	t_{RWL}	40	—	45	—	55	—	ns	
Write Command to $\overline{\text{CAS}}$ Lead Time	t_{CWL}	40	—	45	—	55	—	ns	
Data-in Set-up Time	t_{DS}	0	—	0	—	0	—	ns	9
Data-in Hold Time	t_{DH}	40	—	45	—	55	—	ns	8, 9
Data-in Hold Time referenced to $\overline{\text{RAS}}$	t_{DHR}	100	—	120	—	155	—	ns	
Read Command Set-up Time	t_{RCS}	0	—	0	—	0	—	ns	
Read Command Hold Time referenced to $\overline{\text{CAS}}$	t_{RCH}	0	—	0	—	0	—	ns	
Read Command Hold Time referenced to $\overline{\text{RAS}}$	t_{RRH}	10	—	10	—	10	—	ns	
Refresh Period	t_{REF}	—	4	—	4	—	4	ms	

(to be continued)

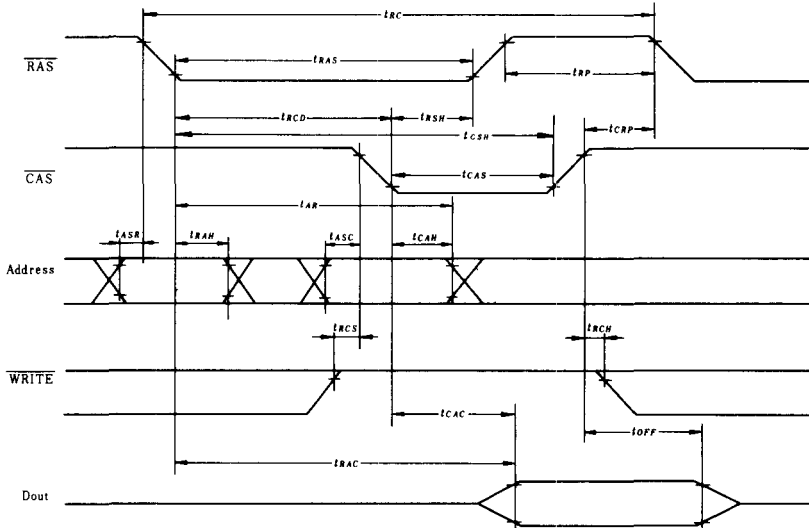
Parameter	Symbol	HM50256/P-12		HM50256/P-15		HM50256/P-20		Unit	Notes
		min	max	min	max	min	max		
Read-Write Cycle Time	t_{RWC}	265	—	310	—	390	—	ns	
CAS to WE Delay	t_{CWD}	60	—	75	—	100	—	ns	8
RAS to WE Delay	t_{RWD}	120	—	150	—	200	—	ns	
CAS Precharge Time	t_{CPN}	50	—	60	—	80	—	ns	
CAS Setup Time	t_{CSR}	10	—	10	—	10	—	ns	
CAS Hold Time (CAS before RAS Refresh)	t_{CHR}	120	—	150	—	200	—	ns	
RAS Precharge to CAS Hold Time	t_{RPC}	0	—	0	—	0	—	ns	

Notes

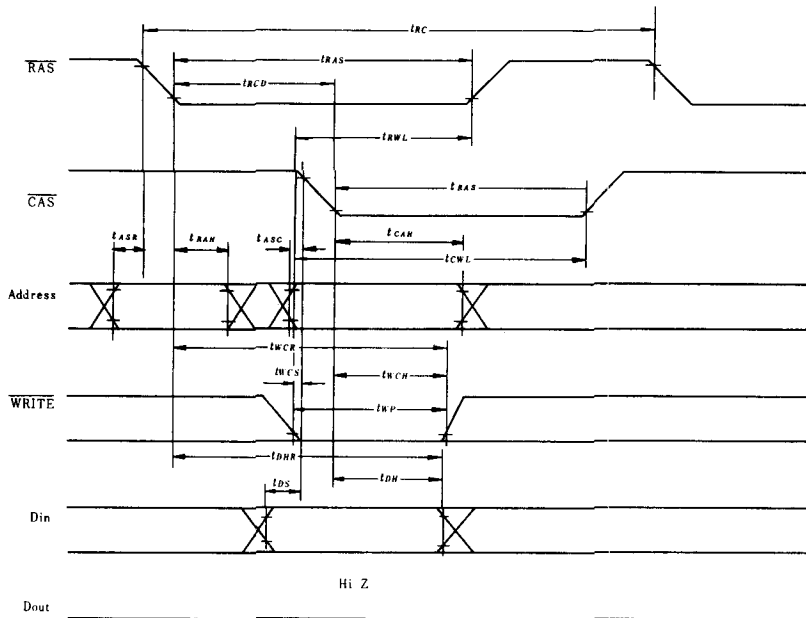
- AC measurements assume $t_T = 5ns$.
- Assumes that $t_{RCD} \leq t_{RCD} (max)$. If t_{RCD} is greater than the maximum recommended value shown in this table, t_{RAC} exceeds the value shown.
- Measured with a load circuit equivalent to 2TTL loads and 100pF.
- Assumes that $t_{RCD} \geq t_{RCD} (max)$.
- t_{OFF} (max) defines the time at which the output achieves the open circuit condition and output voltage levels are not referred.
- V_{IH} (min) and V_{IL} (max) are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL} .
- Operation with the t_{RCD} (max) limit insures that t_{RAC} (max) can be met, t_{RCD} (max) is specified as a reference point only; if t_{RCD} is greater than the specified t_{RCD} (max) limit, access time is controlled exclusively by t_{CAC} .
- t_{WCS} , t_{CWD} and t_{RWD} are not restrictive operating parameters.
They are included in the data sheet as electrical characteristics only; if $t_{WCS} \geq t_{WCS} (min)$, the cycle is an early write cycle and the data output pin will remain open circuit (high impedance) throughout the entire cycle; if $t_{CWD} \geq t_{CWD} (min)$ and $t_{RWD} \geq t_{RWD} (min)$, the cycle is a read-write and the data output will contain data read from the selected cell; if neither of the above sets of conditions is satisfied the condition of the data out (at access time) is indeterminate.
- These parameters are referenced to CAS leading edge in early write cycles and to WE leading edge in delayed write or read-modify-write cycles.
- An initial pause of 100 μs is required after power-up then execute at least 8 initialization cycles.
- At least, 8 CAS before RAS refresh cycle are required before using internal refresh counter.

■ TIMING WAVEFORMS

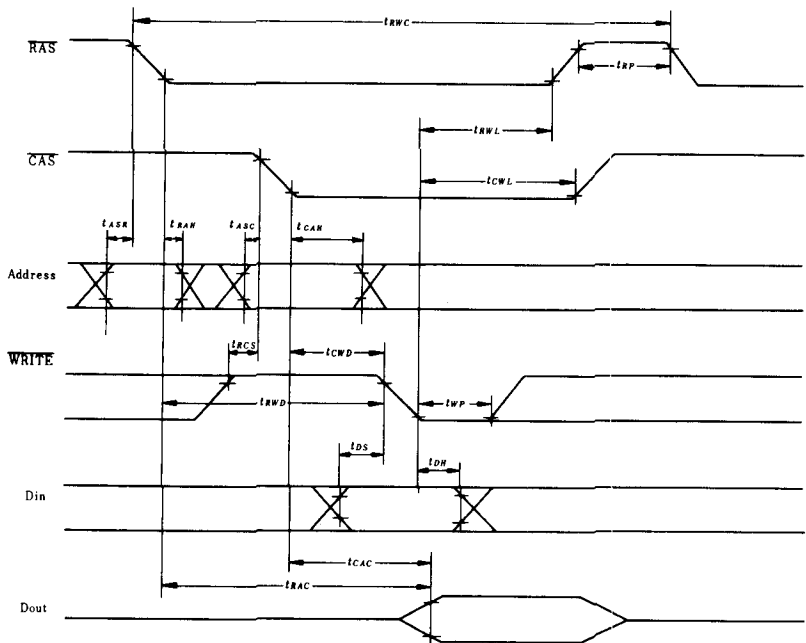
● READ CYCLE



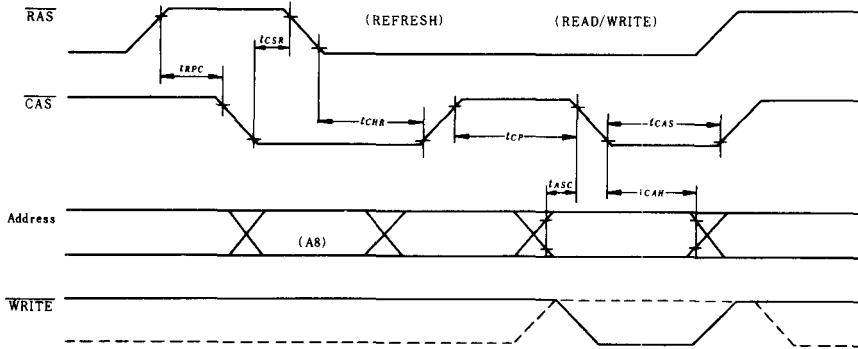
● WRITE CYCLE



● READ MODIFY WRITE CYCLE



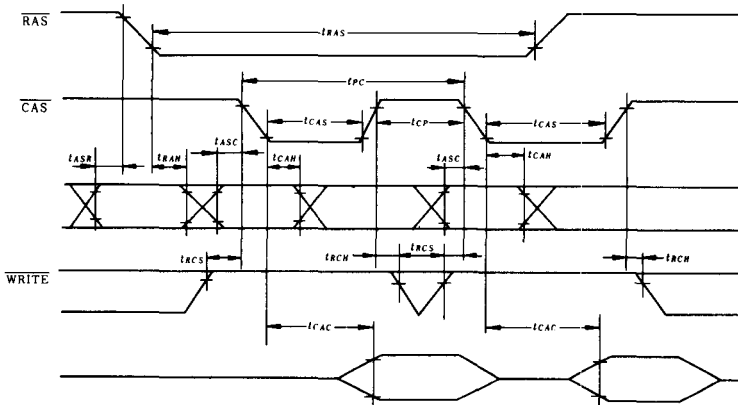
● COUNTER TEST



■ PAGE MODE CHARACTERISTICS ($T_a=0$ to $+70^\circ\text{C}$, $V_{CC}=5\text{V}\pm 10\%$, $V_{SS}=0\text{V}$)

Parameter	Symbol	HM50256/P-12		HM50256/P-15		HM50256/P-20		Unit
		min	max	min	max	min	max	
Page Mode Supply Current	I_{CC1}	—	57	—	48	—	37	mA
Page Mode Read or Write Cycle	t_{PC}	120	—	145	—	190	—	ns
CAS Precharge Time, Page Cycle	t_{CP}	50	—	60	—	80	—	ns
Page Mode Read Modify Write Cycle	t_{PCM}	165	—	195	—	250	—	ns

● PAGE MODE READ CYCLE



● PAGE MODE WRITE CYCLE

